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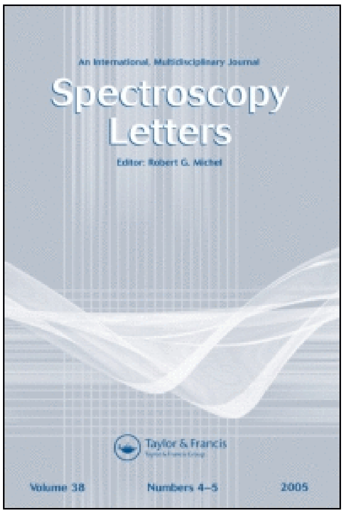

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Advances in X-Ray Analysis Vol 39. Plenum Publishing 1998
Handbook $175 908 p + XVII.

This book is a compilation of papers presented at the 44th Annual Conference on Applications of X-Ray Analysis held August 1995 at Colorado Springs. It consists of 100 papers on topics ranging from Historical Reviews, Conditioning of x-ray beams, Stress and strain determination, Characterization of polymers, Precision and accuracy, Characterization of thin film, X-ray diffraction. Total reflection XRF and Quantitative XRF. Of these papers 61 were invited and 7 described poster sessions.

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